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Sheet	1	of	2
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Application Number	10/765,505
Filing Date	1/26/2004
First Named Inventor	Luu, et al.
Art Unit	2857
Examiner Name	Not Yet Assigned
Attorney Docket Number	SPEED-P001

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Date Considered

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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

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Sheet 2 of 2	Attorney Docket Number		SPEED-P001

ON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
AS	1	TOBIN, et al., Feature Analysis and Classification of Manufacturing Signatures Based on Semiconductor Wafermaps 12 pages.	X
	2	TOBIN, et al., Automatic Classification of Spatial Signatures on Semiconductor Wafermaps 11 pages.	X
	3	KARNOWSKI, et al., Fuzzy Logic Connectivity in Semiconductor Defect Clustering 10 pages.	X
	4	GLEASON, et al., An Integrated Spatial Signature Analysis and Automatic Defect Classification System 8 pages.	X
	5	GLEASON, et al., Rapid Yield Learning through Optical Defect and Electrical Test Analysis 11 pages.	X
	6	TOBIN, et al., An Image Paradigm for Semiconductor Defect Data Reduction 12 pages.	X
	7	TOBIN, et al., Automated Analysis for Rapid Defect Sourcing and Yield Learning 15 pages.	X
	8	TOBIN, et al., Using Historical Wafermap Data for Automated Yield Analysis 16 pages.	X
	9	TOBIN, et al., Adaptation of The Fuzzy K-Nearest Neighbor Classifier for Manufacturing Automation 9 pages.	X
	10	TOBIN, et al., Image Retrieval in the Industrial Environment 9 pages.	X

Examiner Signature	<i>Charles Stevenson</i>	Date Considered	06/06/04
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